

Trace-Element Analysis by Use of PIXE Technique on Agricultural Products

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Purpose

Our group has worked on developing a way to determine production area of foods by analyzing its trace elements with PIXE. We tried to verify that trace elements of soy beans come from the soil of production area.

Experiment

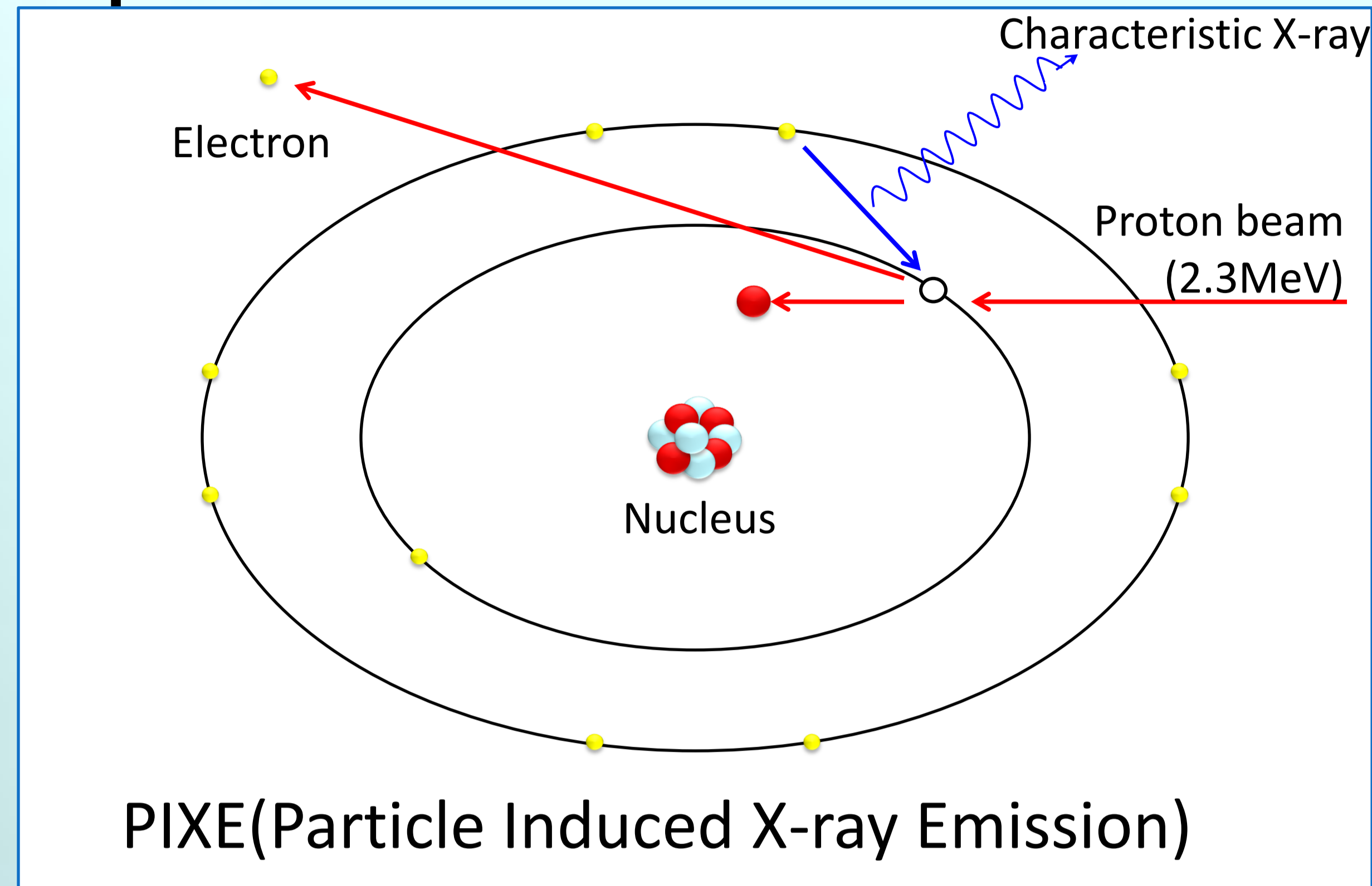
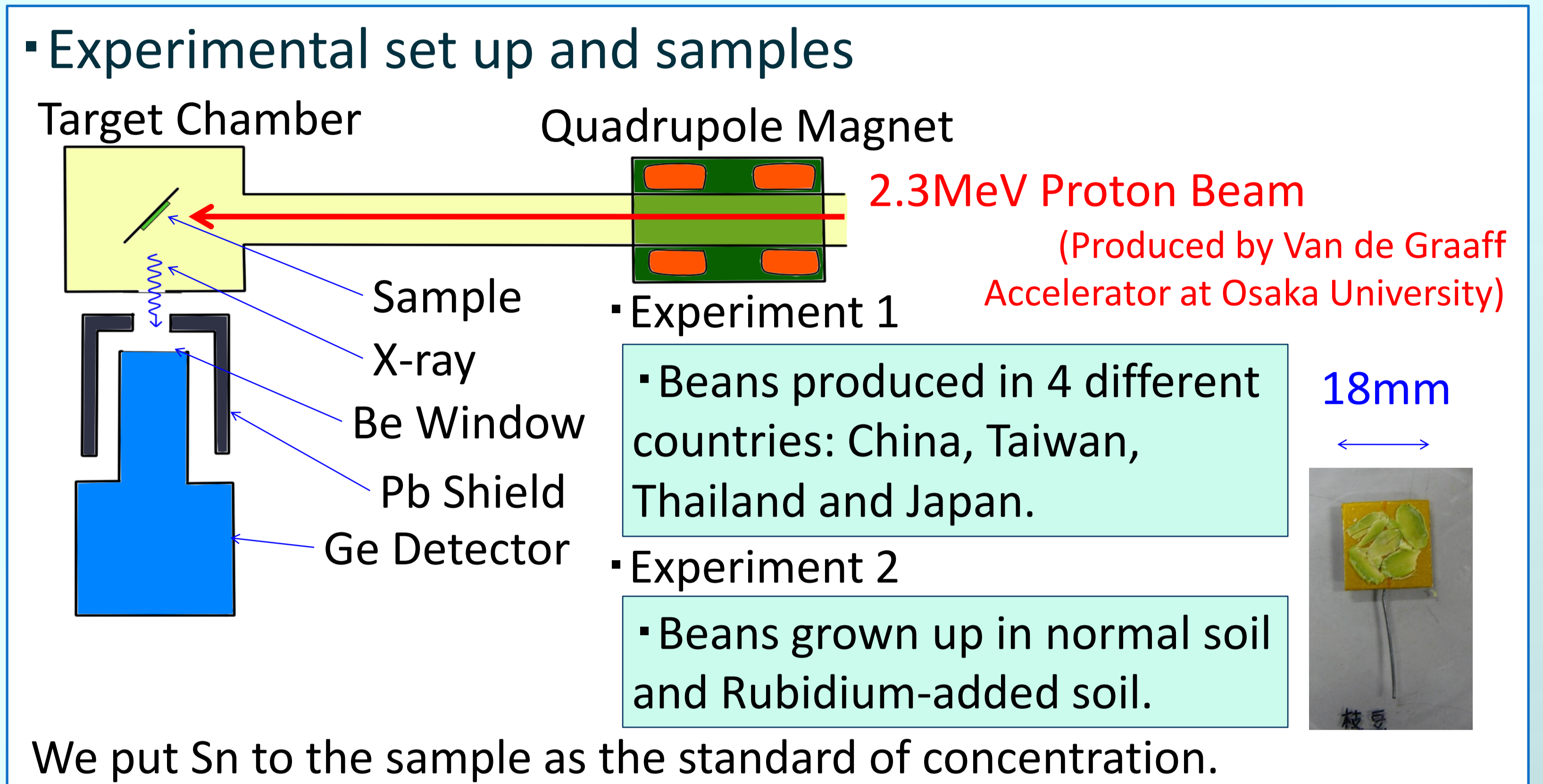
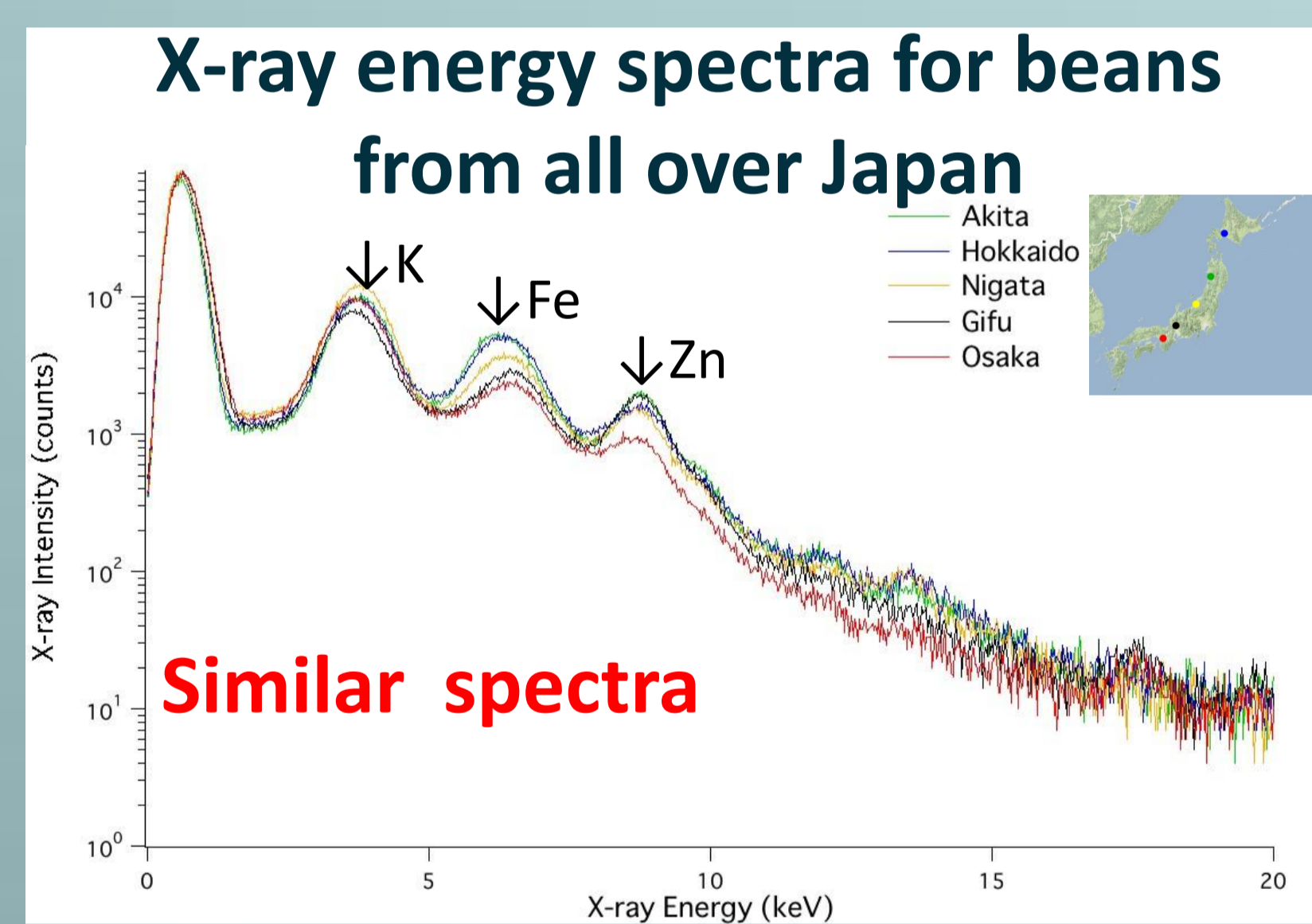
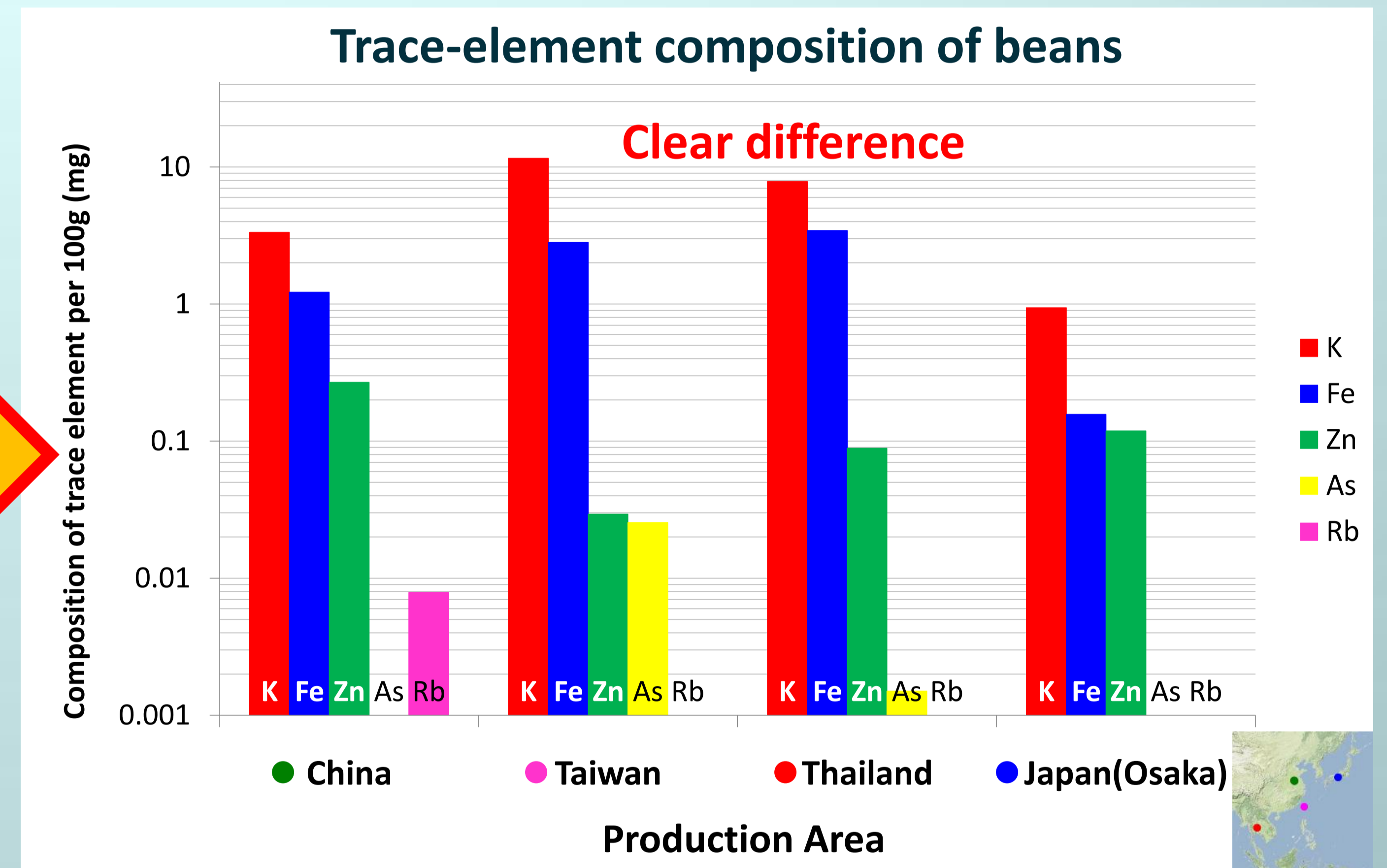
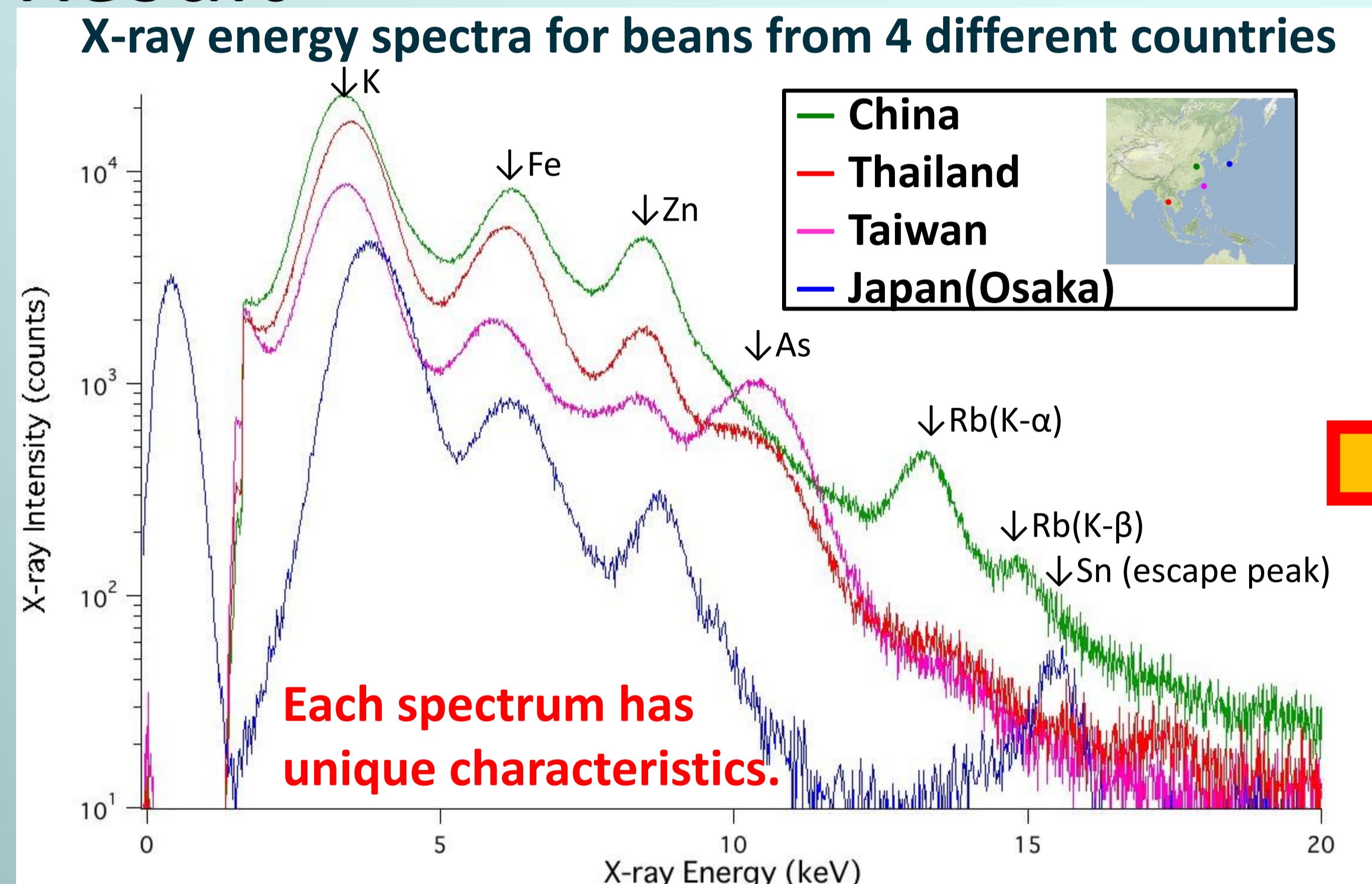


Fig.1: A schematic diagram of PIXE which shows an atom in a sample.

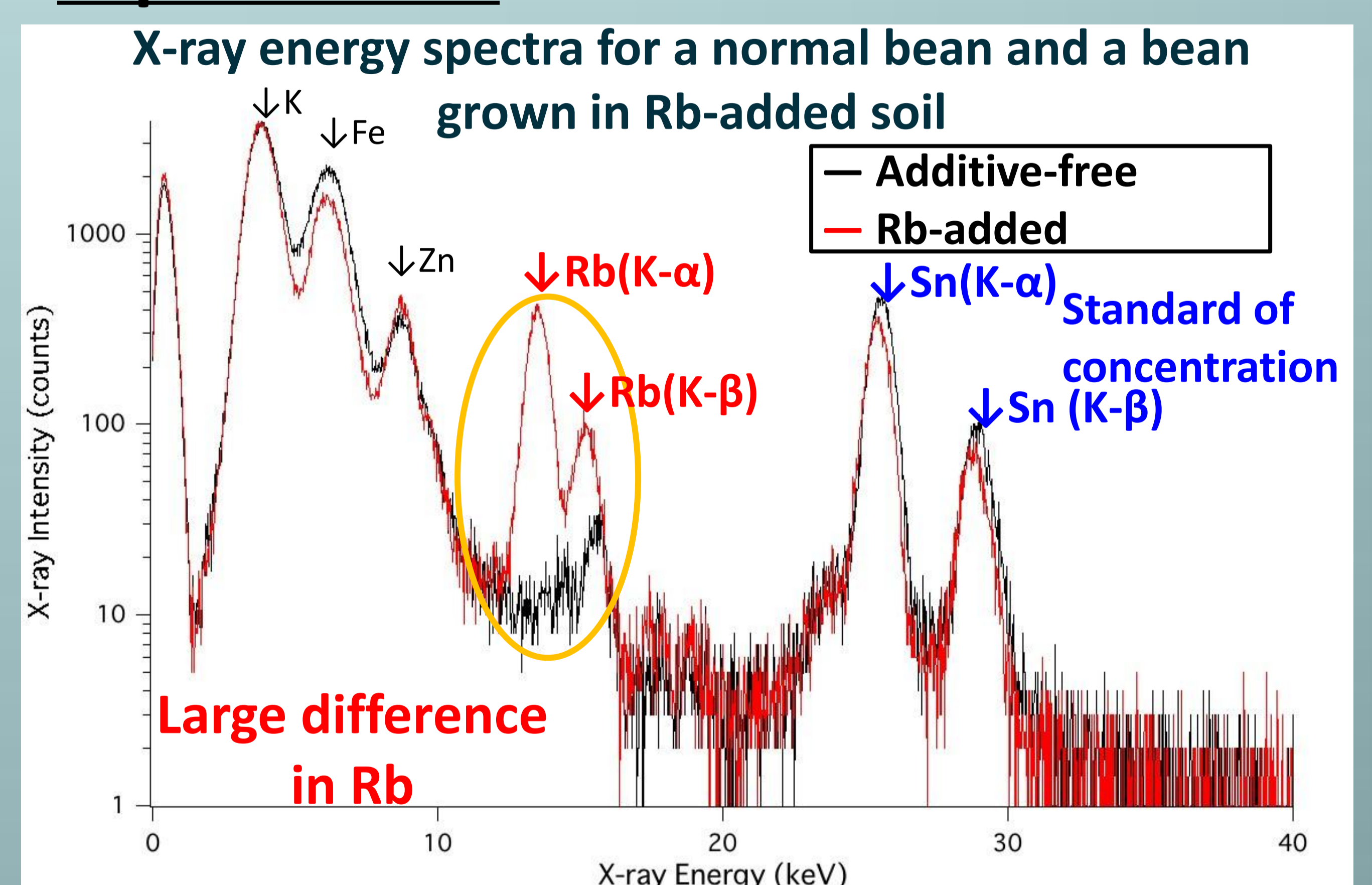


Result



Experiment 1
Difference of trace elements in beans from different area.

Experiment 2



We investigated whether the difference of trace elements is due to the soil. We grew up beans in normal and Rb-added soil.

Analysis

We fit each peak with two Gaussian (K- α and K- β) and linear background to count the number of X-rays. We obtained the concentration of elements by comparing the peaks with that of Sn. Rb of the amount from 0.2mg to 5mg per 100g of beans was detected from the beans grew in Rb-added soil whereas Rb was not detected from beans in normal soil.

Conclusion

We found that differences in concentration of trace elements depend on the production area. The difference is affected by the soil at least concerning with Rb. The PIXE study could be used to distinguish the production area of agricultural products.